

<b>Notice of References Cited</b>	Application/Control No. 10/817,551	Applicant(s)/Patent Under Reexamination SHIN, YONG-SHIK	
	Examiner Thomas M. Redding	Art Unit 2624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sahoo et al. Threshold Selection using a Minimal Histogram Entropy Difference, Optical Engineering 36(7) July 1997, pp 1976-1981
	V	Strang, Calculus, 1991, Wellesley-Cambridge Press, pp 130 - 133
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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